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ELECTRONIC INFORMATION DISCLOSURE STATEMENT

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Title of Invention	CONTINUOUS PROCESSING OF THIN-FILM BATTERIES AND LIKE DEVICES						
Application Number:	09/816603						
Confirmation Number:	6175						
First Named Applicant:	Mark Jenson						
Attorney Docket Number:	1327.009US1						
Art Unit:	1745						
Examiner:	Unknown Unknown						
Search string:	(4353160 or 4440108 or 4520039 or 4633129 or 4684848 or 4862032 or 5017550 or 5022930 or 5064520 or 5089104 or 5098737 or 5115378 or 5261968 or 5273837 or 5296122 or 5314765 or 5348703 or 5393572 or 5455126 or 5482611 or 5501175 or 5501924 or 5512147 or 5528222 or 5529671 or 5536333 or 5561004 or 5567210 or 5569520 or 5569564 or 5585999 or 5593551 or 5597660 or 5599644 or 5601652 or 5612152 or 5654084 or 5705293 or 5830331 or 5863337 or 5868914 or 5935727 or 5981107 or 5995006)						
05/19/2003 HAMTE1 00000049 190743	09816603	6002208 or 6033471 or 6037717 or 6042687 or 6059847 or 6103412 or 6110620 or 6130507 or 6133159 or 6136165 or 6139964 or 6147354					
05/19/2003 HAMTE1 00000049 09816603		or 6153067 or 6181545).pn.					
01 FC:1806	180.00 CH						
01 FC:1806	180.00 CH						
US Patent Documents							
Note: Applicant is not required to submit a paper copy of cited US Patent Documents							
init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	4353160	1980-11-24	Armini, Anthony J., et al.		29	572
	2	4440108	1982-09-24	Little, Roger G., et al.		118	719
	3	4520039	1982-09-23	Ovshinsky, Stanford R.		427	35
	4	4633129	1985-04-30	Cuomo, Jerome J., et al.		313	153
	5	4684848	1985-10-15	Kaufman, Harold R., et al.		315	111.81
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	7	5017550	1988-03-30	Shioya, Jun , et al.		505	1

8	5022930	1989-06-20	Ackerman, Bruce , et al.	136	251
9	5064520	1990-02-14	Miyake, Kiyoshi , et al.	204	192.11
10	5089104	1990-12-03	Kanda, Naoya , et al.	204	192.11
11	5098737	1990-05-09	Collins, Carl B., et al.	427	53.1
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13	5261968	1992-01-13	Jordan, John F.	136	244
14	5273837	1992-12-23	Aitken, Bruce G., et al.	249	30
15	5296122	1992-02-18	Katsube, Teruaki , et al.	204	298.04
16	5314765	1993-10-14	Bates, John B.	429	194
17	5348703	1991-10-11	Bishop, A;an W., et al.	420	590
18	5393572	1994-07-11	Dearnaley, Geoffrey	427	523
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20	5482611	1993-10-08	Helmer, , et al.	204	298.17
21	5501175	1994-07-01	Tanaka, So , et al.	117	108
22	5501924	1995-06-07	Swierbut, Wendi M., et al.	429	224
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25	5529671	1994-07-27	Debley, William P., et al.	204	192.34
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28	5567210	1994-07-12	Bates, John B., et al.	29	623.5
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	48	6042687	1997-06-30	Singh, Vikram , et al.	156	345
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	50	6103412	1998-05-12	Hirano, Shinichi , et al.	429	24
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	54	6136165	1997-11-26	Moslehi, Mehrdad M.	204	298.06
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Signature

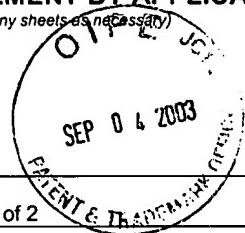
Examiner Name	Date
RAM	09/12/03

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Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)



Complete if Known

Application Number	09/816603
Filing Date	March 23, 2001
First Named Inventor	Jenson, Mark
Group Art Unit	1745
Examiner Name	Unknown

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Sheet 1 of 2

Attorney Docket No: 1327.009US1

TC 1700**US PATENT DOCUMENTS**

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	JP-60182961	02/26/1987	Shiro, Yamauchi , et al.			
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Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		<i>Complete if Known</i>	
		Application Number	09/816603
		Filing Date	March 23, 2001
		First Named Inventor	Jenson, Mark
		Group Art Unit	1745
		Examiner Name	Unknown
Sheet 2 of 2		Attorney Docket No: 1327.009US1	

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✓	WO-95/14311	05/26/1995	Ovshinsky, Stanford R., et al.	H01M	6/18	

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
✓	NOT available	NOMOTO, S., et al., "Back-up Performance of Electric Double-Layer Capacitors for Rechargeable Batteries", <u>Electrochemical Society Proceedings, Volume 96-25 (1997) 268-279</u>	→
RJM	✓	SHODAI, T, et al., "Reaction Mechanisms of Li(2.6)Co(0.4) Anode Material", <u>Solid State Ionics, 122 (1999) 85-93</u> No specific date available	↑

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RJM

DATE CONSIDERED

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